EAST SEARCH

7/2/2007

L#	Hits	Search String	Databases
S1	494501	(chemical or petrochemical or manufacturing) near2 process$2	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S2	573	((chemical or petrochemical or manufacturing) near2 process$2) with (process near2 model$	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S3	785	((chemical or petrochemical or manufacturing) near2 process$2) same (process near2 model	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S4	785	S2 or S3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S5	73	S4 and (integrated near2 model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S6	5	S4 and (symbolic near2 (model$3 or language))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S17	85	S4 and (process with environment with model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S18	0	S4 and ((log or logging) with (assumption or (model near2 transformation)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S7	20	S4 and (symbolic near2 (manipulation or representation or description))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S22	1	S4 and ((rate near2 change) with (mass near2 (vapor or liquid)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S8	2	S4 and (ancestor near2 model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S23	52	S4 and (rate near2 change)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S24	10	S4 and (energy near2 (vapor or liquid))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S25	6	S4 and ((pressure or thermal) near2 equilibrium)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S27	4	S4 and ("equal pressure" or "gas law" or "volume correlation")	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S29	207	S9 or S13	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S30	153	S28 and S29	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S9	132	S4 and ((specific or environment) near2 model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S31	306	S28 or S30	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S32	20	S31 and (S6 or S7)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S33	2	S31 and S8	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S34	3	S4 and (formal near2 language)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S38	9	S4 and (model near2 transformation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S40	2	S31 and S20	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S41	3	S31 and S21	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S45	4	S31 and S27	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S10	33	S4 and ((formal near2 language) or (equation near2 based))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S11	8	S4 and (Mathematica or Axiom or MAPLE or ADIFOR)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S12	35	S4 and (generic near2 (model$3 or component))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S13	142	S4 and (model$3 with (assumption or environment))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S14	2	S4 and (component near2 specific near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S15	65	S4 and (component near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S16	9	S4 and (environment near2 independent)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S19	75	S4 and (log or logging)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S20	2	S4 and (flash near2 column)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S21	3	S4 and (parameter near2 representation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S26	6	S4 and ((vapor or liquid) near2 (enthalpy or heat))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S28	306	S5 or S6 or S7 or S8 or S10 or S11 or S12 or S14 or S15 or S16 or S17 or S19 or S20 or S2	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S35	3	S31 and S34	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S36	8	S31 and S11	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S37	85	S31 and S17	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB

S39	7	S31 and S38	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S42	3	S4 and (mass near2 (vapor or liquid))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S44	6	S31 and S25	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S43	10	S31 and (S24 or S42)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S74	306	S71 or S73	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S46	573	((chemical or petrochemical or manufacturing) near2 process$2) with (process near2 model$	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S68	6	S48 and ((pressure or thermal) near2 equilibrium)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S65	1	S48 and ((rate near2 change) with (mass near2 (vapor or liquid)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S64	3	S48 and (parameter near2 representation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S67	10	S48 and (energy near2 (vapor or liquid))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S66	52	S48 and (rate near2 change)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S63	2	S48 and (flash near2 column)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S62	75	S48 and (log or logging)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S61	85	S48 and (process with environment with model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S60	9	S48 and (environment near2 independent)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S59	65	S48 and (component near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S58	2	S48 and (component near2 specific near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S57	142	S48 and (model$3 with (assumption or environment))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S56	35	S48 and (generic near2 (model$3 or component))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S55	8	S48 and (Mathematica or Axiom or MAPLE or ADIFOR)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S54	33	S48 and ((formal near2 language) or (equation near2 based))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S53	132	S48 and ((specific or environment) near2 model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S52	2	S48 and (ancestor near2 model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S51	20	S48 and (symbolic near2 (manipulation or representation or description))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S50	5	S48 and (symbolic near2 (model$3 or language))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S49	73	S48 and (integrated near2 model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S48	785	S46 or S47	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S47	785	((chemical or petrochemical or manufacturing) near2 process$2) same (process near2 model	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S73	153	S71 and S72	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S72	207	S53 or S57	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S71	306	S49 or S50 or S51 or S52 or S54 or S55 or S56 or S58 or S59 or S60 or S61 or S62 or S63 c	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S70	4	S48 and ("equal pressure" or "gas law" or "volume correlation")	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S69	6	S48 and ((vapor or liquid) near2 (enthalpy or heat))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S88	106	S77 and (process with environment with model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S91	4	S77 and (parameter near2 representation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S94	11	S77 and (energy near2 (vapor or liquid))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S95	7	S77 and ((pressure or thermal) near2 equilibrium)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S97	4	S77 and ("equal pressure" or "gas law" or "volume correlation")	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S98	360	S78 or S79 or S80 or S81 or S82 or S83 or S84 or S85 or S86 or S87 or S88 or S89 or S90 c	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S102	33	S99 and S101	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S103	47	S100 or S102	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S80	21	S77 and (symbolic near2 (manipulation or representation or description))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S79	6	S77 and (symbolic near2 (model$3 or language))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S84	40	S77 and (generic near2 (model$3 or component))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S81	2	S77 and (ancestor near2 model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S77	915	S75 or S76	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S76	915	((chemical or petrochemical or manufacturing) near2 process$2) same (process near2 model	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB

S78	83	S77 and (integrated near2 model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S75	665	((chemical or petrochemical or manufacturing) near2 process$2) with (process near2 model$	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S86	74	S77 and (component near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S87	14	S77 and (environment near2 independent)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S89	88	S77 and (log or logging)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S90	2	S77 and (flash near2 column)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S92	1	S77 and ((rate near2 change) with (mass near2 (vapor or liquid)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S93	61	S77 and (rate near2 change)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S96	11	S77 and ((vapor or liquid) near2 (enthalpy or heat))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S101	120	S77 and (specific near2 model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S99	100	S77 and ((generic or general or universal) near2 model$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S82	41	S77 and ((formal near2 language) or (equation near2 based))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S100	22	S77 and (model$3 with assumption)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S85	2	S77 and (component near2 specific near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S83	8	S77 and (Mathematica or Axiom or MAPLE or ADIFOR)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB

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Results of search set S91:

Document Kind Codes	Title	Issue Date	Current OR	Abstract
US 20060195213 A1	Method of operating an advanced process controller by dynamically adapting hierarchy levels	20060831	700/108	
US 20060190913 A1	Method and apparatus for identifying a manufacturing problem area in a layout using a gradie	20060824	716/19	
US 20060190223 A1	SAMPLE PROBABILITY OF FAULT FUNCTION DETERMINATION USING CRITICAL DEFE	20060824	703/2	
US 20060190222 A1	PROBABILITY OF FAULT FUNCTION DETERMINATION USING CRITICAL DEFECT SIZE I	20060824	703/2	
US 20060178528 A1	Method of controlling acetic acid process	20060810	562/519	
US 20060172427 A1	Method and apparatus for retrofitting existing real time control systems for monitoring, control	20060803	436/55	
US 20060150129 A1	Stochastic analysis process optimization for integrated circuit design and manufacture	20060706	716/4	
US 20060136138 A1	Creation and maintenance of a history list in a method and apparatus for integrated modeling	20060622	702/19	
US 20060124156 A1	Carbon dioxide snow apparatus	20060615	134/99.1	
US 20060117654 A1	Bench scale apparatus to model and develop biopharmaceutical cleaning procedures	20060608	47/58.1SC	
US 20060117067 A1	System and method for interactive visual representation of information content and relationsh	20060601	707/104.1	
US 20060111804 A1	Multivariate control of semiconductor processes	20060525	700/110	
US 20060106757 A1	Search for similar sheet metal part models	20060518	707/2	
US 20060106485 A1	Enhanced digital process design methodology for process centric CAD systems	20060518	700/182	
US 20060103378 A1	Apparatus and method for dynamic diagnostic testing of integrated circuits	20060518	324/228	
US 20060101370 A1	METHOD FOR IMPROVING OPTICAL PROXIMITY CORRECTION	20060511	716/19	
US 20060100873 A1	CIRCUIT STATISTICAL MODELING FOR PARTIALLY CORRELATED MODEL PARAMETEI	20060511	704/256.2	
US 20060074603 A1	Customer support system and method of customer support	20060406	702/188	
US 20060074599 A1	Application of abnormal event detection technology to olefins recovery trains	20060406	702/185	
US 20060074598 A1	Application of abnormal event detection technology to hydrocracking units	20060406	702/185	
US 20060073013 A1	Application of abnormal event detection technology to fluidized catalytic cracking unit	20060406	416/35	
US 20060069958 A1	Defect location identification for microdevice manufacturing and test	20060330	714/33	
US 20060069541 A1	Reuse of manufacturing process design models as part of a diagnostic system	20060330	703/22	
US 20060058898 A1	System and method for abnormal event detection in the operation of continuous industrial prc	20060316	700/29	
US 20060015294 A1	Data collection and analysis system	20060119	702/183	

US 20060014394 A1	Process for low temperature, dry etching, and dry planarization of copper	20060119	438/710
US 20050272640 A1	Method and apparatus for glucose control and insulin dosing for diabetics	20051208	514/3
US 20050270199 A1	Method for designing mixed signal integrated circuits and configurable synchronous digital nc	20051208	341/120
US 20050268256 A1	Modeling resolution enhancement processes in integrated circuit fabrication	20051201	716/4
US 20050267723 A1	Physiocochemical process modelling system	20051201	703/11
US 20050261888 A1	Time dependent process parameters for integrated process and product engineering	20051124	703/22
US 20050261887 A1	Time dependent process parameters and engineering change number conflict report	20051124	703/22
US 20050261791 A1	Interfaces from external systems to time dependent process parameters in integrated proces:	20051124	700/97
US 20050235246 A1	Use of models in integrated circuit fabrication	20051020	716/21
US 20050234586 A1	Predictive modeling of machining line variation	20051020	700/159
US 20050228511 A1	Computer-implemented system and method for measuring and improving manufacturing proc	20051013	700/28
US 20050209834 A1	Horizontally structured CAD/CAM modeling-vertical to horizontal conversion	20050922	703/2
US 20050187747 A1	Method and apparatus for improved simulation of chemical and biochemical reactions	20050825	703/11
US 20050187746 A1	Method and apparatus for improved modeling of chemical and biochemical reactions	20050825	703/11
US 20050187745 A1	Method and apparatus facilitating communication with a simulation environment	20050825	703/11
US 20050187717 A1	Method and apparatus for integrated modeling, simulation and analysis of chemical and biocl	20050825	702/19
US 20050187643 A1	Parametric universal nonlinear dynamics approximator and use	20050825	700/29
US 20050181342 A1	Medical training simulator including contact-less sensors	20050818	434/262
US 20050159934 A1	Integrated modeling through symbolic manipulation	20050721	703/2
US 20050154477 A1	Kiln control and upset recovery using a model predictive control in series with forward chainin	20050714	700/37
US 20050132306 A1	Characterization and reduction of variation for integrated circuits	20050616	716/1
US 20050120010 A1	System and method for determining costs within an enterprise	20050602	707/3
US 20050065767 A1	Closed loop integration of digital models of in silico systems and experimental procedures	20050324	703/22
US 20050065626 A1	Material reservation distribution system and method	20050324	700/97
US 20050060584 A1	Trusted infrastructure support systems, methods and techniques for secure electronic comme	20050317	726/4
US 20050045029 A1	Selective separation of fluid compounds utilizing a membrane separation process	20050303	95/46
US 20050037522 A1	Dummy fill for integrated circuits	20050217	438/8
US 20050010319 A1	System and method for validating and visualizing APC assisted semiconductor manufacturing	20050113	700/121
US 20050004687 A1	Apparatus and method of controlling multi-input-single-output systems	20050106	700/44
US 20040256230 A1	Microfluidic devices for transverse electrophoresis and isoelectric focusing	20041223	204/450
US 20040230411 A1	Apparatus and methods for predicting properties of processed material	20041118	703/6
US 20040220691 A1	Method and apparatus for constructing crowns, bridges and implants for dental use	20041104	700/98
US 20040220689 A1	Sensor placement and control design for distributed parameter systems	20041104	700/97
US 20040210429 A1	Apparatus and methods for performing process simulation using a hybrid model	20041021	703/9
US 20040182786 A1	Purification of fluid compounds utilizing a distillation - membrane separation process	20040923	210/640
US 20040167763 A1	Information processing method for evaluating biochemical pathway models using clinical data	20040826	703/11
US 20040154965 A1	Wet and dry weather water flows disinfection system	20040812	210/85
US 20040153296 A1	Horizontally structured CAD/CAM coordinate system	20040805	703/2
US 20040153202 A1	Horizontally structured manufacturing process modeling: across file feature operability	20040805	700/182
US 20040153201 A1	Horizontally structured CAD/CAM coordinate system for manufacturing design	20040805	700/182
US 20040153200 A1	Horizontally structured manufacturing process modeling: exterior linked representational emb	20040805	700/182
US 20040153197 A1	Modeling an abrasive process to achieve controlled material removal	20040805	700/164
US 20040148047 A1	Hierarchical methodology for productivity measurement and improvement of productions syst	20040729	700/100
US 20040139419 A1	Minimization of microelectronic interconnect thickness variations	20040715	716/20
US 20040130276 A1	System and method of applying adaptive control to the control of particle accelerators with va	20040708	315/501
US 20040128003 A1	SYSTEM AND METHOD FOR MODEL BASED CONTROL OF A NEURAL NETWORK	20040701	700/31
US 20040128002 A1	SYSTEM AND METHOD FOR MODEL BASED CONTROL OF A CHEMICAL PROCESS	20040701	700/31
US 20040123129 A1	Trusted infrastructure support systems, methods and techniques for secure electronic comme	20040624	713/193

US 20040121495 A1	Dynamic adaptive sampling rate for model prediction	20040624	438/14
US 20040117040 A1	System and method of adaptive control of processes with varying dynamics	20040617	700/29
US 20040102935 A1	Method for regulating a property of a product derived from a chemical transformation	20040527	703/2
US 20040099213 A1	Spatially programmable microelectronics process equipment using segmented gas injection s	20040527	118/715
US 20040093107 A1	Probability constrained optimization for electrical fabrication control	20040513	700/108
US 20040088149 A1	Method and apparatus for performing OPC using model curvature	20040506	703/13
US 20040088065 A1	Cooperative smart items	20040506	700/95
US 20040083452 A1	Method and system for predicting multi-variable outcomes	20040429	717/109
US 20040083028 A1	Process control using on-line instrumentation and process models	20040429	700/269
US 20040076944 A1	Supervised learning in the presence of null data	20040422	434/433
US 20040068342 A1	Method of designing and manufacturing rubber process tooling using an interface to a CAD/C	20040408	700/182
US 20040068332 A1	Stochastic modeling of spatial distributed sequences	20040408	700/51
US 20040034555 A1	Hierarchical methodology for productivity measurement and improvement of complex product	20040219	705/7
US 20040034517 A1	DEVICE MODELING FOR PROXIMITY EFFECTS	20040219	703/14
US 20040028253 A1	Detoxification of solid freeform fabrication materials	20040212	381/322
US 20040015335 A1	Method, system and medium for controlling manufacturing process using adaptive models ba	20040122	703/2
US 20030237064 A1	Characterization and verification for integrated circuit designs	20031225	716/5
US 20030229881 A1	Adjustment of masks for integrated circuit fabrication	20031211	716/19
US 20030229880 A1	Test masks for lithographic and etch processes	20031211	716/19
US 20030229875 A1	Use of models in integrated circuit fabrication	20031211	716/10
US 20030229868 A1	Electronic design for integrated circuits based process related variations	20031211	716/5
US 20030229412 A1	Electronic design for integrated circuits based on process related variations	20031211	700/121
US 20030229410 A1	Integrated circuit metrology	20031211	700/109
US 20030200064 A1	One-dimensional modeling of the manufacture of multi-layered material	20031023	703/2
US 20030195708 A1	Method for analyzing an unknown material as a blend of known materials calculated so as to	20031016	702/22
US 20030149502 A1	Method and system for creating a tooling master model for manufacturing parts	20030807	700/98
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US 20030144758 A1	System and method for integrating geometric models	20030731	700/104
US 20030136201 A1	Patient monitoring system employing array of force sensors on a bedsheet or similar substrat	20030724	73/862.41
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US 20030114950 A1	System, method and computer program product for mapping data of multi-database origins	20030619	700/108
US 20030100972 A1	Reusable software components for invoking computational models	20030529	700/121
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US 20030023403 A1	Process for estimating random error in chemical and biological assays when random error dif	20030130	702/179
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US 20030004596 A1	Horizontally-structured CAD/CAM modeling for virtual concurrent product and process design	20030102	700/98
US 20020199123 A1	Security architecture for a process control platform executing applications	20021226	726/3

US 20020198920 A1	Supervisory process control and manufacturing information system application having a layer	20021226	718/100
US 20020198697 A1	Universal epistemological machine (a.k.a. android)	20021226	704/1
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US 20020194393 A1	Method of determining causal connections between events recorded during process executio	20021219	719/318
US 20020171176 A1	Detoxification of solid freeform fabrication materials	20021121	264/401
US 20020165636 A1	Systems and methods for metrology recipe and model generation	20021107	700/121
US 20020156757 A1	Electronic product design system	20021024	707/1
US 20020156542 A1	Methods, devices and systems for monitoring, controlling and optimizing processes	20021024	700/30
US 20020152000 A1	Automated horizontally structured manufacturing process design modeling	20021017	700/98
US 20020136822 A1	Method and apparatus for monitoring the coating on particle during manufacturing of a pharm	20020926	427/8
US 20020133803 A1	Enhancement to horizontally-structured CAD/CAM modeling	20020919	717/104
US 20020133267 A1	Enhancement to horizontally structured manufacturing process modeling	20020919	700/182
US 20020133266 A1	Horizontally structured manufacturing process modeling for alternate operations, large parts ε	20020919	700/182
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US 20020133253 A1	Horizontally-structured CAD/CAM modeling for virtual fixture and tooling processes	20020919	700/98
US 20020133252 A1	Horizontally structured manufacturing process modeling for fixtures and tooling	20020919	700/97
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US 20020077719 A1	Variable parameter controls for semiconductor processes	20020620	700/117
US 20020072872 A1	Method for diagnosing process parameter variations from measurements in analog circuits	20020613	702/117
US 20020072828 A1	Computer method and apparatus for constraining a non-linear approximator of an empirical p	20020613	700/269
US 20020059003 A1	System, method and computer program product for mapping data of multi-database origins	20020516	700/19
US 20020052858 A1	Method and tool for data mining in automatic decision making systems	20020502	706/15
US 20020038163 A1	Apparatus and method for managing and distributing design and manufacturing informatiion t	20020328	700/165
US 20010025232 A1	Hybrid linear-neural network process control	20010927	703/13
US 20010020395 A1	Patient monitoring system employing array of force sensors on a bedsheet or similar substrat	20010913	73/862.041
US 7110956 B1	Capability predictor	20060919	705/7
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US 7089075 B2	Systems and methods for metrology recipe and model generation	20060808	700/121
US 7079908 B2	Horizontally-structured modeling for analysis	20060718	700/98
US 7070694 B2	Purification of fluid compounds utilizing a distillation - membrane separation process	20060704	210/640
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US 7039475 B2	System and method of adaptive control of processes with varying dynamics	20060502	700/31
US 7037172 B1	Advanced wafer planarizing	20060502	451/5
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US 20030097243 A1	Method and system for operating a hydrocarbon production facility	20030522	703/2
US 20030061015 A1	Stochastic modeling of time distributed sequences	20030327	703/2
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US 20020143417 A1	Characteristic adjusting method in process of manufacturing products	20021003	700/95
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L3	3	1 and (symbolic near2 (model$3 or language))	US-PGPUB
L4	7	1 and (symbolic near2 (manipulation or representation or description))	US-PGPUB
L5	4	1 and (Mathematica or Axiom or MAPLE or ADIFOR)	US-PGPUB
L6	23	1 and (generic near2 (model$3 or component))	US-PGPUB
L7	80	1 and (specific near2 model$3)	US-PGPUB
L8	40	1 and (component near2 model)	US-PGPUB
L9	23	1 and (generic near2 (model$3))	US-PGPUB
L10	17	7 and 8	US-PGPUB
L11	95	3 or 4 or 5 or 6 or 7 or 9 or 10	US-PGPUB
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L16	1	11 and (Axiom.CLM.)	US-PGPUB
L17	1	11 and (MAPLE.CLM.)	US-PGPUB
L18	1	11 and (ADIFOR.CLM.)	US-PGPUB
L19	25	12 or 13 or 14 or 15 or 16 or 17 or 18	US-PGPUB

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US 20070092854 A1	Methods for manufacturing dental implant components	20070426	433/213	
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... in figure 7, the monolithic task-**specific model** of parametric ... being able to add the **axiom** below, which ... we have reconstructed the **generic model** of parametric ...
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... 4). The two axioms, **Axiom** 1 and **Axiom** 2, ensure the appropriate relationships ... 9 and **Axiom** 3). A consistent design model does not violate any constraint (Def. ...
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... For this to be a **specific model** of the **generic model** described in part by Figure 1, the types of ... This rela- tionship is expressed by the following **axiom**: ...
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... effects, modal captivity and consistency with the independence from irrelevant alternatives **axiom** (IIA), which excludes the possibility of complemen- ...
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... from the group consisting of Mathematica, **Axiom**, MAPLE and ... of claim 1 wherein the **generic model** comprises a ... of claim 1 wherein the **specific model** comprises a ...
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... The proof of this **axiom** is rather trivial. ... model (or paradigm) for the task-**specific model** provided by ... and F. Frayman: Towards a **Generic Model** of Configuration ...
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... A **generic model** in which the ... of student models employed in this paper into general models, a reasoning procedure (RP) and a situation-**specific model** (Fig. ...
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... Model (PIM) and Platform **Specific Model** (PSM ... to enable their extensibility, integration and **generic model** and metamodel ... Given an **axiom** CbD, the algorithm first ...
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... 2.1 **Axiom**-based interference model ... This **specific model**, which holds eg for multi-antenna beamforming ... functions in Section 2. This **generic model** contains the ...
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... On the other hand, any **specific model** will have specific details which could ... Together with **axiom** preserving signature morphisms this yields a category SPEC of ...
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... 1 The purpose of the "reducibility **axiom**" [16] is precisely to postulate that one can always replace an impredicative definition by a predicative one. ...
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